Programmable logic sequencer $(20 \times 45 \times 12)$

PLS179

DESCRIPTION

The PLS179 is a 3-State output, registered logic element combining AND/OR gate arrays with clocked J-K flip-flops. These J-K flip-flops are dynamically convertible to D-type via a "foldback" inverting buffer and control gate, F_C. It features 8 registered I/O outputs (F) in conjunction with 4 bidirectional I/O lines (B). There are 8 dedicated inputs. These yield variable I/O gate and register configurations via control gates (D, L) ranging from 20 inputs to 12 outputs.

The AND/OR arrays consist of 32 logic AND gates, 13 control AND gates, and 21 OR gates with fusible link connections for programming I/O polarity and direction. All AND gates are linked to 8 inputs (I), bidirectional I/O lines (B), internal flip-flop outputs (O), and the Complement Array output (C). The Complement Array consists of a NOR gate optionally linked to all AND gates for generating and propagating complementary AND terms.

On-chip T/C buffers couple either True (I, B, Q) or Complement (I, B, Q, C) input polarities to all AND gates, whose outputs can be optionally linked to all OR gates. Any of the 32 AND gates can drive bidirectional I/O lines (B), whose output polarity is individually programmable through a set of EX-OR gates for implementing AND-OR or AND-NOR logic functions. Similarly, any of the 32 AND gates can drive the J-K inputs of all flip-flops. Four AND gates have been dedicated for the Asynchronous Preset/Reset functions.

All flip-flops are positive edge-triggered and can be used as input, output or I/O (for interfacing with a bidirectional data bus) in conjunction with load control gates (L), steering inputs (I), (B), (Q) and programmable output select lines (E).

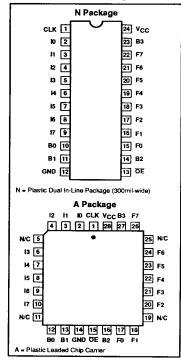
The PLS179 is field programmable, enabling the user to quickly generate custom patterns using standard programming equipment.

Order codes are listed below.

FEATURES

- f_{MAX} = 18.2MHz
 25MHz clock rate
- Field-Programmable (Ni-Cr link)
- 8 dedicated inputs
- 13 control gates
- 32 AND gates
- 21 OR gates
- 45 product terms:
- 32 logic terms
- 13 control terms
- 4 bidirectional I/O lines
- 8 bidirectional registers
- J/K, T, or D-type flip-flops
- Asynchronous Preset/Reset
- Complement Array
- Active-High or -Low outputs
- Programmable OE control
- Positive edge-triggered clock
- Power-on reset on flip-flop (F_n = "1")
- Input loading: 100µA (max.)
- Power dissipation: 750mW (typ.)
- TTL compatible
- 3-State outputs

PIN CONFIGURATIONS



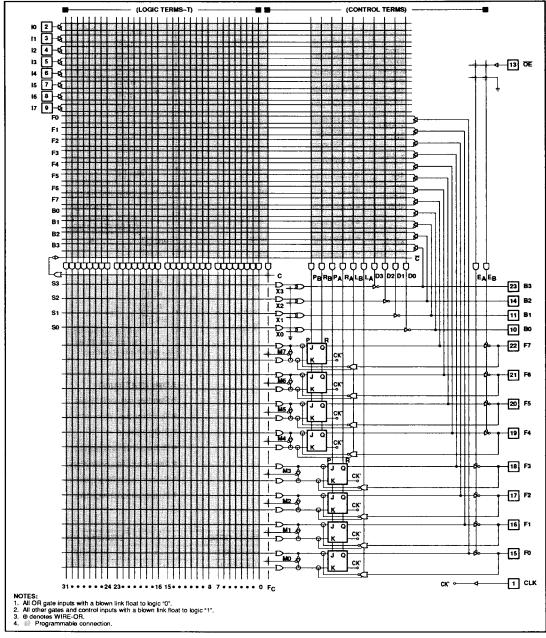
APPLICATIONS

- Random sequential logic
- Synchronous up/down counters
- Shift registers
- Bidirectional data buffers
- Timing function generators
- System controllers/synchronizers
- Priority encoder/registers

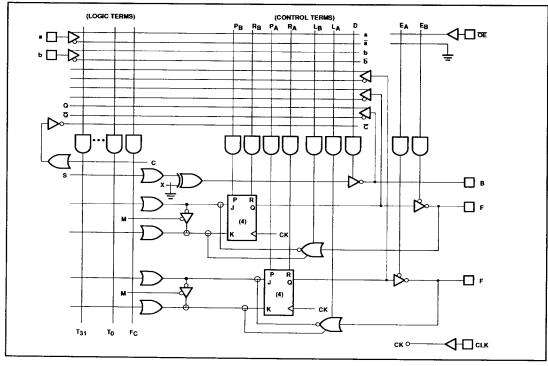
ORDERING INFORMATION

DESCRIPTION	ORDER CODE	DRAWING NUMBER		
24-Pin Plastic Dual In-Line Package (300mil-wide)	PLS179N	0410D		
28-Pin Plastic Leaded Chip Carrier	PLS179A	0401F		

LOGIC DIAGRAM



FUNCTIONAL DIAGRAM



FLIP-FLOP TRUTH TABLE

OE	L	CK	P	R	J	K	Q	F
Н								H/Hi-Z
L	x	Х	Х	X	Х	Χ	L	Н
L	x	Х	н	L	Х	Х	Н	L
L	×	X	L	Н	Х	Х	L	н
L	L	1	L	L	L	L	Q	۵
L	L	1	L	L	L	Н	L	н
L	L	1	Ł	L	н	L,	н	L
L	L	1	L	L	Н	Н	ਧ	Q
н	Н	1	L	L	L	Н	L	H*
Н	Н	1	L	L	Н	L	н	L*
+10V	х	1	Х	Х	L.	Н	L	H* *
	х	1	Х	X	н	L	н	F

- J. Positive Logic:
 J-K = T₀ + T₁ + T₂ T₃₁
 T_n = C (I0 · I1 · I2 ...) · (Q₀ · Q₁ ...) ·
 (B0 · B1 · ...)
 2. T denotes transition from Low to High level.

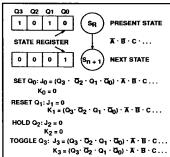
- 3. X = Don't care
 4. *= Forced at F_n pin for loading the J-K flip-flop in the Input mode. The load control term, Ln must be enabled (HIGH) and the p-terms that are connected to the associated flip-flop must be forced LOW (disabled) during Preload.
- 5. At P = R = H, Q = H. The final state of Q
- depends on which is released first.

 * * = Forced at F_n pin to load J-K flip-flop independent of program code (Diagnostic mode), 3-State B outputs.

Programmable logic sequencer $(20 \times 45 \times 12)$

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LOGIC FUNCTION



NOTE:

Similar logic functions are applicable for D and T mode flip-flops.

VIRGIN STATE

The factory shipped virgin device contains all fusible links intact, such that:

- 1. OE is always enabled.
- 2. Preset and Reset are always disabled.
- 3. All transition terms are disabled.
- All flip-flops are in D-mode unless otherwise programmed to J-K only or J-K or D (controlled).
- All B pins are inputs and all F pins are outputs unless otherwise programmed.

THERMAL RATINGS

TEMPERATURE						
Maximum junction	150°C					
Maximum ambient	75°C					
Allowable thermal rise ambient to junction	75°C					

ABSOLUTE MAXIMUM RATINGS¹

SYMBOL		RATI	RATINGS		
	PARAMETER	MIN	MAX	UNIT	
V _{CC}	Supply voltage		+7	V _{DC}	
V _{IN}	Input voltage		+5.5	V _{DC}	
V _{OUT}	Output voltage		+5.5	V _{DC}	
I _{IN}	Input currents	-30	+30	mA	
lout	Output currents		+100	mA	
T _{amb}	Operating temperature range	0	+75	°C	
T _{stg}	Storage temperature range	-65	+150	⊸c	

Stresses above those listed may cause malfunction or permanent damage to the device. This is a stress rating only. Functional operation at these
or any other condition above those indicated in the operational and programming specification of the device is not implied.

Programmable logic sequencer $(20 \times 45 \times 12)$

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DC ELECTRICAL CHARACTERISTICS

 $0^{\circ}\text{C} \le \text{T}_{amb} \le +75^{\circ}\text{C}, 4.75\text{V} \le \text{V}_{CC} \le 5.25\text{V}$

SYMBOL	PARAMETER	TEST CONDITION	MIN	MIN TYP1		UNIT
Input volt	age ²	-				
VIH	High	V _{CC} = MAX	2.0			
VIL	Low	V _{CC} = Min		1	0.8	V
V _{IC}	Clamp	V _{CC} = MIN, I _{IN} = -12mA	- 1	-0.8	-1.2	٧
Output vo	ltage ²					
V _{OH}	High	V _{CC} = MIN, I _{OH} = -2mA	2.4			v
V _{OL}	Low ⁵	I _{OL} = 10mA	l	0.35	0.5	v
Input curr	ent					
l _{IH}	High	V _{CC} = MAX, V _{IN} = 5.5V		<1	40	μА
I _{IL}	Low	V _{IN} = 0.45V		-10	-100	μA
Output cu	rrent		<u> </u>	<u></u>		
lo(OFF)	Hi-Z state ^{4, 7}	V _{CC} = MAX, V _{OUT} = 5.5V	Ţ	1	80	μΑ
		V _{OUT} = 0.45V			-140	μΑ
los	Short circuit ^{3, 5}	V _{OUT} = 0V	-15		-70	•
Icc	V _{CC} supply current ⁶	<u> </u>	-15	l	-	mA.
	L	V _{CC} = MAX		150	210	mA
Capacitan	ce			-		
CIN	Input	V _{CC} = 5.0V, V _{IN} = 2.0V		8		pF
COUT	Output	V _{OUT} = 2.0V	- 1	15	1	pF

- All typical values are at V_{CC} = 5V, T_{amb} = +25°C.
 All voltage values are with respect to network ground terminal.
- 3. Test one at a time.
 4. Measured with V_{IH} applied to OE.
- Duration of short circuit should not exceed 1 second.
 lcc is measured with the OE input grounded, all other inputs at 4.5V and the outputs open.
- Leakage values are a combination of input and output leakage.

AC ELECTRICAL CHARACTERISTICS

 $R_1 = 470\Omega,~R_2 = 1k\Omega,~C_L = 30pF,~0^{\circ}C \leq T_{amb} \leq +75^{\circ}C,~4.75^{\circ}CV \leq V_{CC} \leq 5.25V$

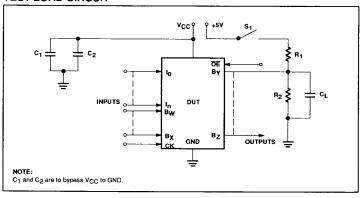
SYMBOL	PARAMETER	FROM	то	TEST	LIMITS			UNIT
				CONDITION	MIN ⁵	TYP1	MAX	
Pulse wid	th ³			1	•			
t _{CKH}	Clock ² High	CK+	CK-	C _L = 30pF	20	15		ns
t _{CKL}	Clock Low	CK-	CK+	C _L = 30pF	20	15		ns
t _{CKP}	Clock period	CK+	CK+	C _L = 30pF	40	30		ns
t _{PRH}	Preset/Reset pulse	(I, B)	(I, B) +	C _L = 30pF	35	30		ns
Setup time	•		•		•		·	-
t _{IS1}	Input	(I, B) ±	CK+	C _L = 30pF	35	30		ns
t _{IS2}	Input (through F _n)	F±	CK+	C _L = 30pF	15	10		ns
t _{IS3}	Input (through Complement Array)4	(I, B) ±	CK+	C _L = 30pF	55	45		ns
Hold time					·•	•		
t _{iH1}	Input	(I, B) ±	CK+	C _L = 30pF	0	5		ns
t_{1H2}	Input (through F _n)	F±	CK+	C _L = 30pF	15	10		ns
Propagation	on delay			4	1		<u> </u>	
tско	Clock	CK±	F±	C _L = 30pF		15	20	ns
t _{OE1}	Output enable ³	QE -	F-	C _L = 30pF		20	30	ns
t _{OD1}	Output disable ³	Œ+	F+	C _L = 5pF		20	30	ns
t _{PD}	Output	(I, B) ±	В±	C _L = 30pF		25	35	ns
t _{OE2}	Output enable ³	(I, B) +	В±	C _L = 30pF		20	30	ns
t _{OD2}	Output disable ³	(i, B) –	B+	C _L = 5pF		20	30	ns
t _{PRO}	Preset/Reset	(I, B) +	F±	C _L = 30pF	1	35	45	ns
tppR	Power-on preset	V _{CC} +	F-	C _L = 30pF		0	10	ns

NOTES:

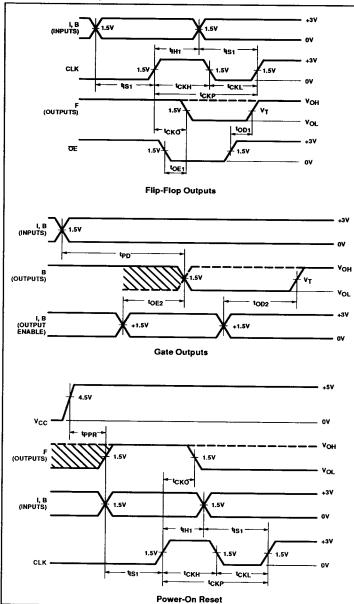
- 1. All typical values are at $V_{CC} = 5V$, $T_{amb} = +25$ °C.
- To prevent spurious clocking, clock rise time (10% 90%) ≤ 10ns.
- 3. For 3-State output, output enable times are tested with C_L = 30pF to the 1.5V level, and S₁ is open for high-impedance to High tests and closed for high-impedance to Low tests. Output disable times are tested with C_L = 5pF. High-to-High impedance tests are made to an output voltage of V_T = (V_{OH} 0.5V) with S₁ open, and Low-to-High impedance tests are made to the V_T = (V_{OL} + 0.5V) level with S₁ closed.
- When using the Complement Array t_{CKP} = 75ns (min).
 Limits are guaranteed with 12 product terms maximum connected to each sum term line.

VOLTAGE WAVEFORMS

TEST LOAD CIRCUIT



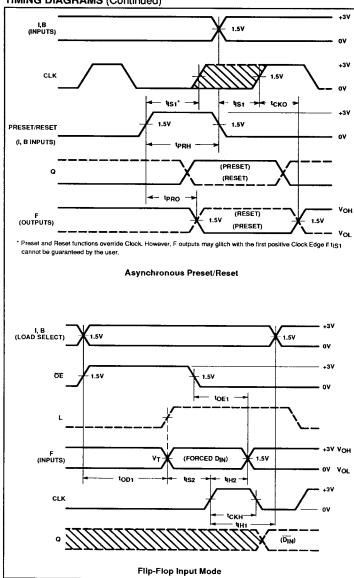
TIMING DIAGRAMS



TIMING DEFINITIONS

TIMING DEFINITIONS						
SYMBOL	PARAMETER					
tскн	Width of input clock pulse.					
t _{CKL}	Interval between clock pulses.					
t _{CKP}	Minimum guaranteed Clock period.					
t _{PRH}	Width of preset input pulse.					
t _{iS1}	Required delay between beginning of valid input and positive transition of clock.					
t _{IS2}	Required delay between beginning of valid input forced at flip-flop output pins, and positive transition of clock.					
t _{IH1}	Required delay between positive transition of clock and end of valid input data.					
t _{iH2}	Required delay between positive transition of clock and end of valid input data forced at flip-flop output pins.					
tско	Delay between positive transition of clock and when outputs become valid (with OE Low).					
t _{OE1}	Delay between beginning of Output Enable Low and when outputs become valid.					
t _{OD1}	Delay between beginning of Output Enable High and when outputs are in the OFF-State.					
tерд	Delay between V _{CC} (after power-on) and when flip-flop outputs become preset at "1" (internal Q outputs at "0").					
t _{PD}	Propagation delay between combinational inputs and outputs.					
t _{OE2}	Delay between predefined Output Enable High, and when combinational Outputs become valid.					
t _{OD2}	Delay between predefined Output Enable Low and when combinational Outputs are in the OFF-State.					
t PRO	Delay between positive transition of predefined Preset/Reset input, and when flip-flop outputs become valid.					





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PLS179

LOGIC PROGRAMMING

The PLS179 is fully supported by industry standard (JEDEC compatible) PLD CAD tools, including Philips Semiconductors' SNAP, Data I/O Corporation's ABEL™ and Logical Devices Inc.'s CUPL™ design software packages.

All packages allow Boolean and state equation entry formats. SNAP, ABEL and CUPL also accept, as input, schematic capture format.

PLS179 logic designs can also be generated using the program table entry format detailed on the following pages. This program table entry format is supported by the Philips Semiconductors SNAP PLD design software package.

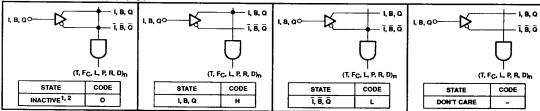
To implement the desired logic functions, the state of each logic variable from logic equations (I, B, O, P, etc.) is assigned a symbol. The symbols for TRUE,

COMPLEMENT, INACTIVE, PRESET, etc., are defined below.

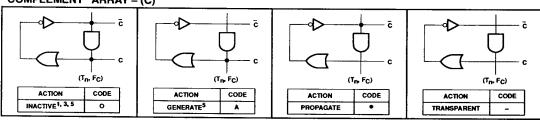
PROGRAMMING AND SOFTWARE SUPPORT

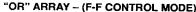
Refer to Section 9 (Development Software) and Section 10 (Third-party Programmer/ Software Support) of this data handbook for additional information.

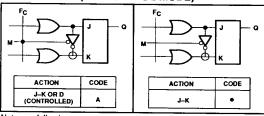
"AND" ARRAY - (I), (B), (Qp)



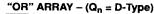


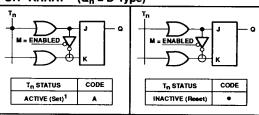


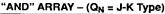


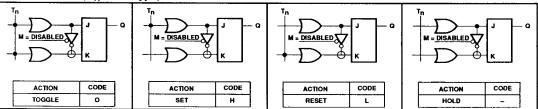


Notes on following page.

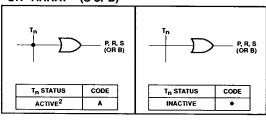




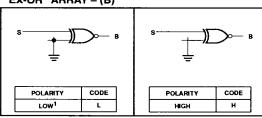




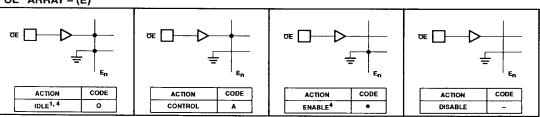






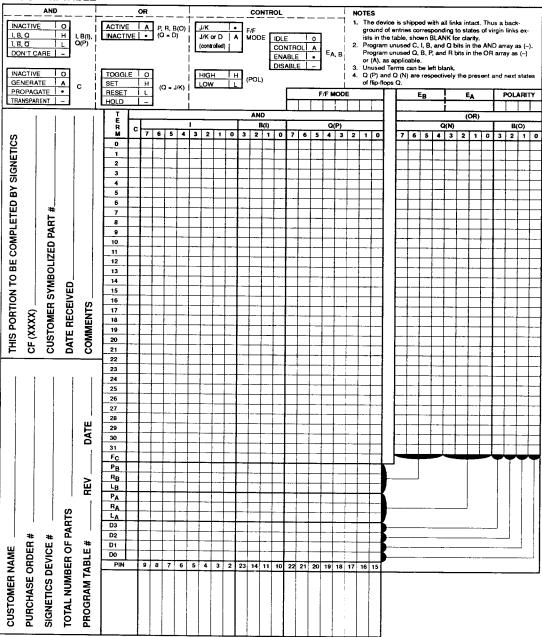


"OE" ARRAY - (E)



- This is the initial unprogrammed state of all link pairs. It is normally associated with all unused (inactive) AND gates.
- 2. Any gate (T, Fc, L, P, R, D)_n will be unconditionally inhibited if any one of the I, B, or Q link pairs are left intact.
- To prevent oscillations, this state is not allowed for C link pairs coupled to active gates T_n , F_C . $E_n = O$ and $E_n = \bullet$ are logically equivalent states, since both cause F_n outputs to be unconditionally enabled. 5. These states are not allowed for control gates (L, P, R, D)_n due to their lack of "OR" array links.

PROGRAM TABLE



SNAP RESOURCE SUMMARY DESIGNATIONS

